

**Notice of References Cited**

Application/Control No.

10/649,676

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

Wesley D Markham

Art Unit

1762

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,144,795	11-2000	Dawes et al.	385/141
	B	US-2003/0228120	12-2003	Kuramoto et al.	385/132
	C	US-2004/0071426	04-2004	Etienne, Pascal	385/129
	D	US-6,492,540	12-2002	Su et al.	556/30
	E	US-2003/0195321	10-2003	Zha, Congji	528/10
	F	US-2003/0165710	09-2003	Kuramoto et al.	428/689
	G	US-2004/0008960	01-2004	Rantala, Juha T.	385/129
	H	US-2004/0033309	02-2004	Fardad et al.	427/162
	I	US-5,783,319	07-1998	Reisfeld et al.	428/690
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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